

Search Notes

Application/Control No.

10/654,770

Examiner

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Applicant(s)/Patent under Reexamination

PARK ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	696	8/22/2005	BT
438	697	8/22/2005	BT
438	700	8/22/2005	BT
438	710	8/22/2005	BT
438	718	8/22/2005	BT

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	8/22/2005	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner